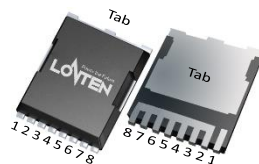
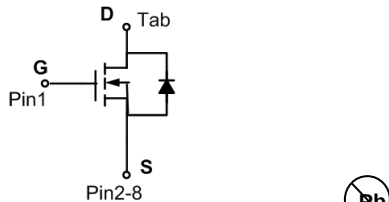


Lonten N-channel 85V, 300A, 1.85mΩ Power MOSFET

Description These N-Channel enhancement mode power field effect transistors are using shielded gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.	Product Summary <table> <tr> <td>V_{DS}</td><td>85V</td></tr> <tr> <td>$R_{DS(on).max}@ V_{GS}=10V$</td><td>1.85mΩ</td></tr> <tr> <td>I_D</td><td>300A</td></tr> </table>	V_{DS}	85V	$R_{DS(on).max}@ V_{GS}=10V$	1.85mΩ	I_D	300A
V_{DS}	85V						
$R_{DS(on).max}@ V_{GS}=10V$	1.85mΩ						
I_D	300A						
Features ◆ 85V,300A,$R_{DS(on).max}=1.85m\Omega@V_{GS} = 10V$ ◆ Improved dv/dt capability ◆ Fast switching ◆ 100% EAS Guaranteed ◆ Green device available Applications ◆ Motor Drives ◆ UPS ◆ DC-DC Converter ◆ Energy Storage	Pin Configuration  TOLL  N-Channel MOSFET						

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	85	V
Continuous drain current ($T_C = 25^\circ\text{C}$,Silicon limit)	I_D	305	A
($T_C = 25^\circ\text{C}$, Package limit)		300	A
($T_C = 100^\circ\text{C}$,Silicon limit)		193	A
Pulsed drain current ¹⁾	I_{DM}	900	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	1568	mJ
Power Dissipation	P_D	313	W
Storage Temperature Range	T_{STG}	-55 to +150	$^\circ\text{C}$
Operating Junction Temperature Range	T_J	-55 to +150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.4	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient ³⁾	$R_{\theta JA}$	50.8	$^\circ\text{C/W}$

Package Marking and Ordering Information

Device	Device Package	Marking
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LSGT085R018	TOLL	LSGT085R018
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Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0 V, I _D =250μA	85	---	---	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2.5	---	4.5	V
Drain-source leakage current	I _{DSS}	V _{DS} =85 V, V _{GS} =0 V, T _J = 25°C	---	---	1	μA
		V _{DS} =85 V, V _{GS} =0 V, T _J = 150°C	---	---	10	mA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =20 V, V _{DS} =0 V	---	---	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-20V, V _{DS} =0 V	---	---	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =90 A, T _J = 25°C	---	1.5	1.85	mΩ
		T _J = 150°C	---	2.7	---	
Forward transconductance	g _{fs}	V _{DS} =5V, I _D =50A	---	45.3	---	S
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} = 42.5V, V _{GS} = 0 V, f = 250kHz	---	13477	---	pF
Output capacitance	C _{oss}		---	1984	---	
Reverse transfer capacitance	C _{rss}		---	62	---	
Turn-on delay time	t _{d(on)}	V _{DD} = 42.5V, V _{GS} =10V, I _D =50 A	---	134	---	ns
Rise time	t _r		---	227	---	
Turn-off delay time	t _{d(off)}		---	178	---	
Fall time	t _f		---	109	---	
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, f=1MHz	---	1.5	---	Ω
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DS} =68 V, I _D =50A, V _{GS} = 10 V	---	65.4	---	nC
Gate to drain charge	Q _{gd}		---	60.2	---	
Gate charge total	Q _g		---	213	---	
Gate plateau voltage	V _{plateau}		---	5.3	---	V
Output Charge	Q _{oss}	V _{DS} =68 V, V _{GS} = 0V	---	256	---	nC
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I _S		---	---	285	A
Pulsed Source Current	I _{SM}		---	---	1140	A
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =50A, T _J =25°C	---	---	1.1	V
Reverse Recovery Time	t _{rr}	I _S =50A, di/dt=100A/μs, T _J =25°C	---	67.9	---	ns
Reverse Recovery Charge	Q _{rr}		---	116	---	nC

Notes:

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2: V_{DD}=150V, V_{GS}=10V, L=1mH, I_{AS}=56A, R_G=25Ω, Starting T_J=25°C.
- 3: The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

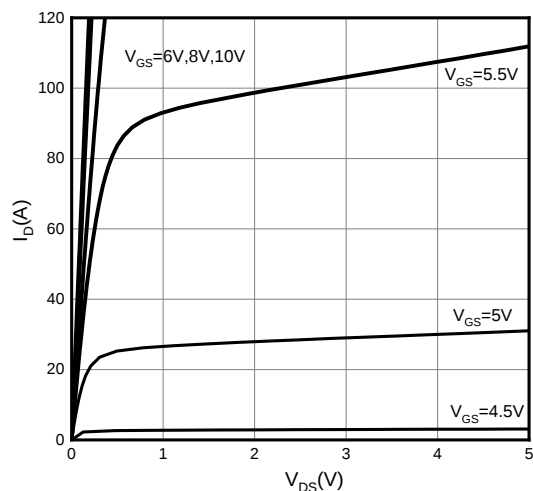


Figure 2. Transfer Characteristics

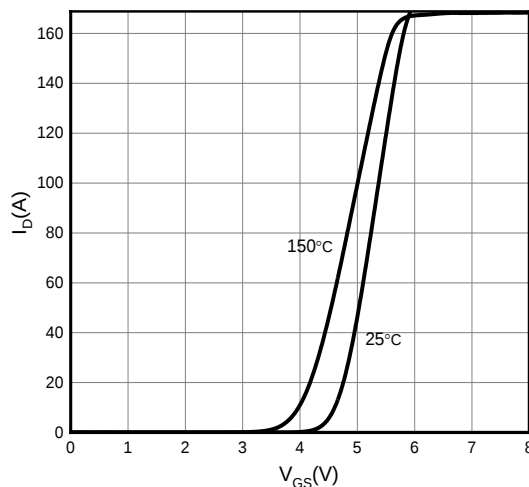


Figure 3. On-Resistance vs. Drain Current

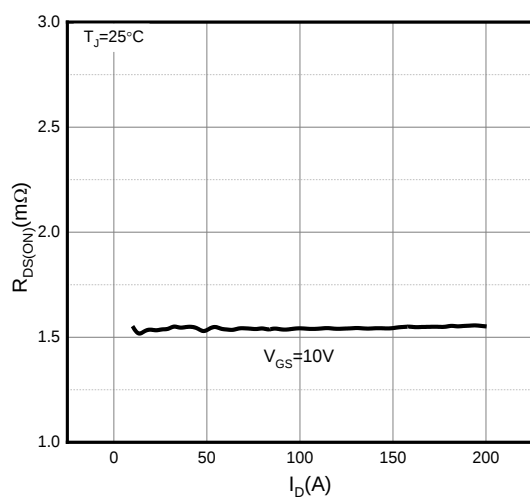


Figure 4. On-Resistance vs. Temperature

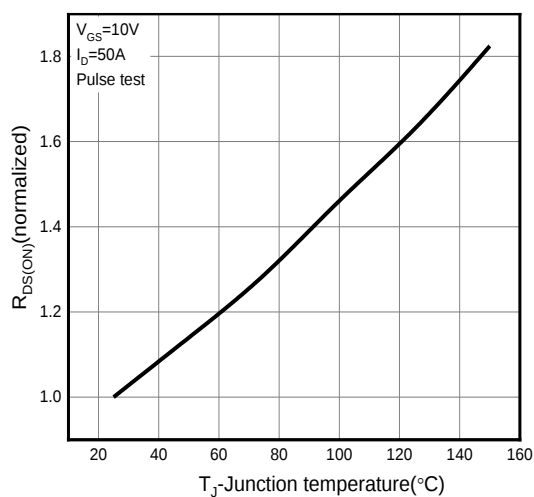


Figure 5. Breakdown Voltage vs. Temperature

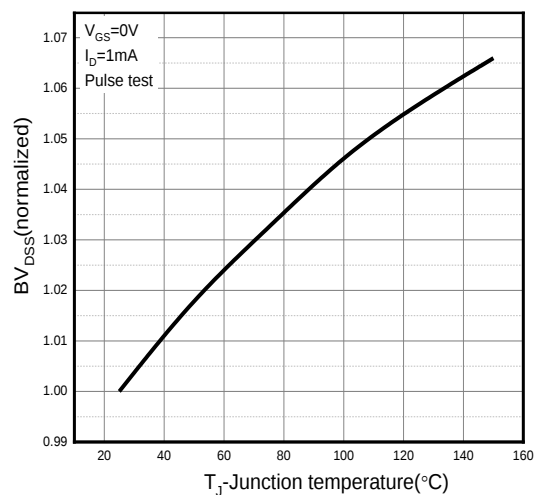


Figure 6. Threshold Voltage vs. Temperature

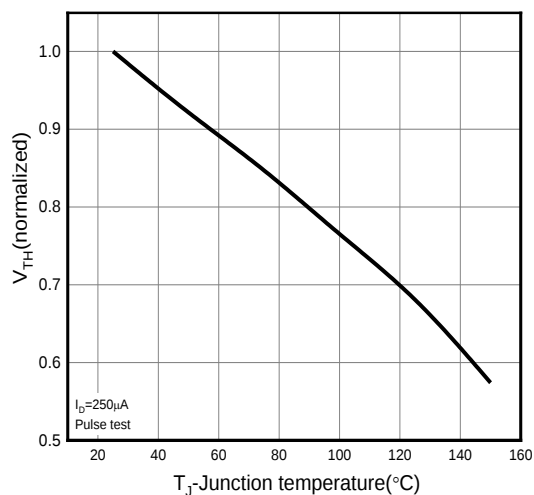


Figure 7. $R_{DS(on)}$ vs. Gate Voltage

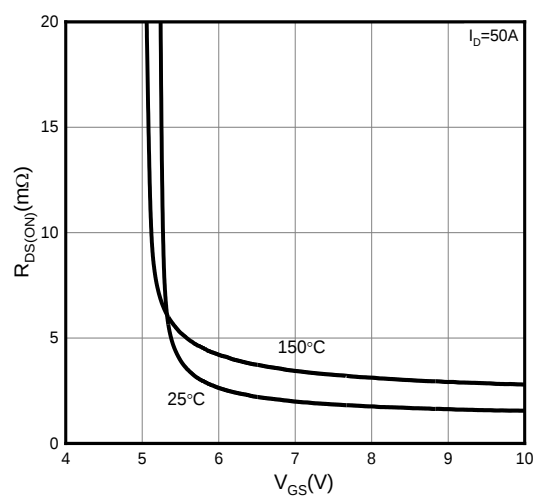


Figure 8. Body-Diode Characteristics

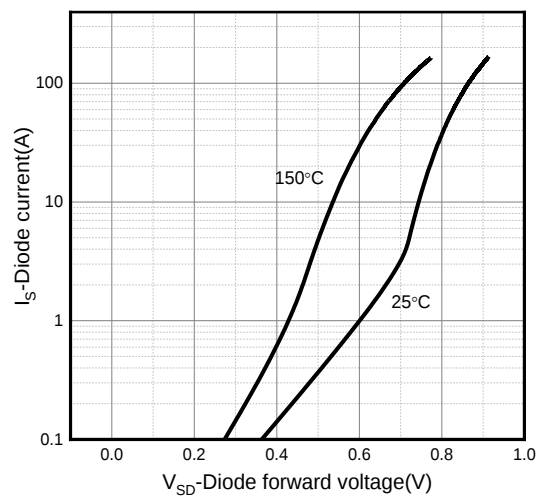


Figure 9. Capacitance Characteristics

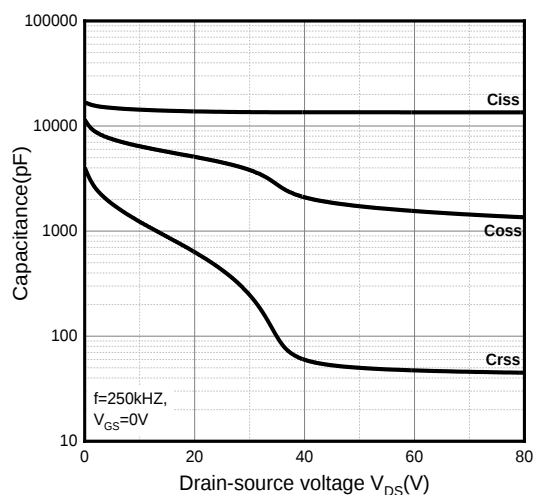


Figure 10. Gate Charge Characteristics

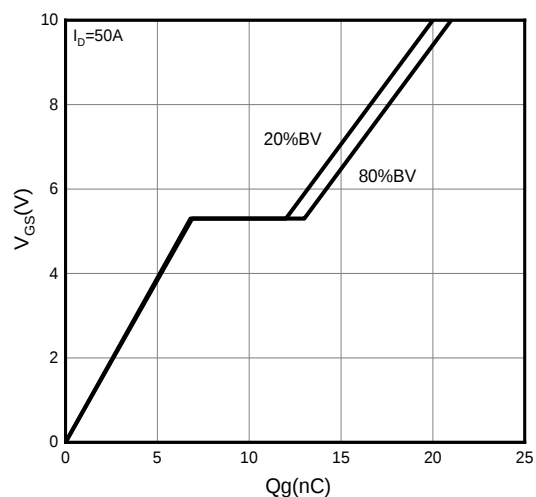


Figure 11. Drain Current Derating

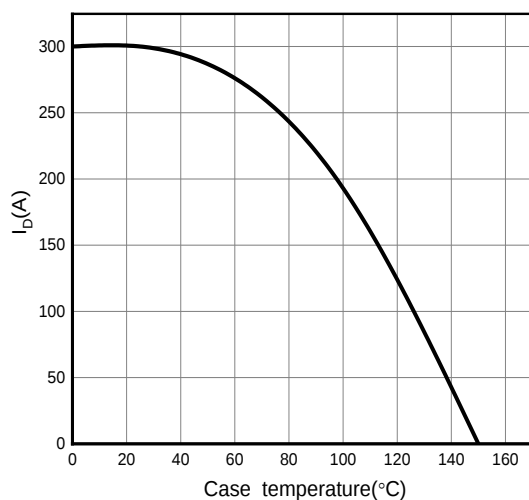


Figure 12. Power Dissipation vs. Temperature

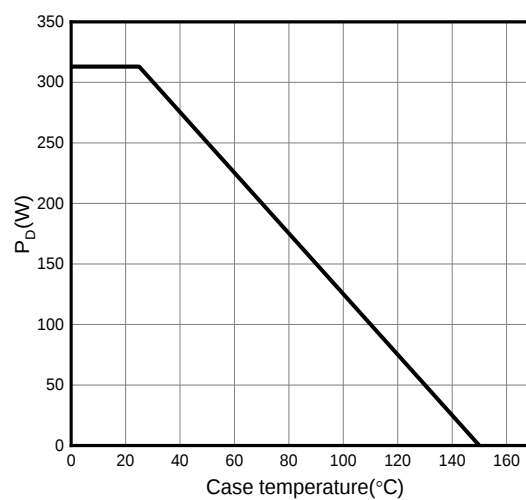


Figure 13. Safe Operating Area

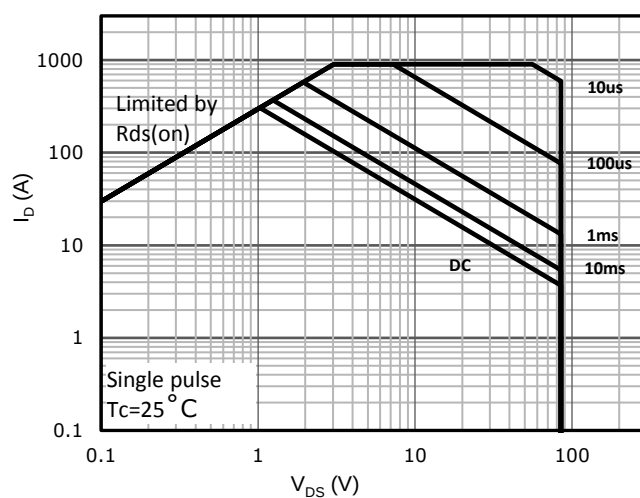
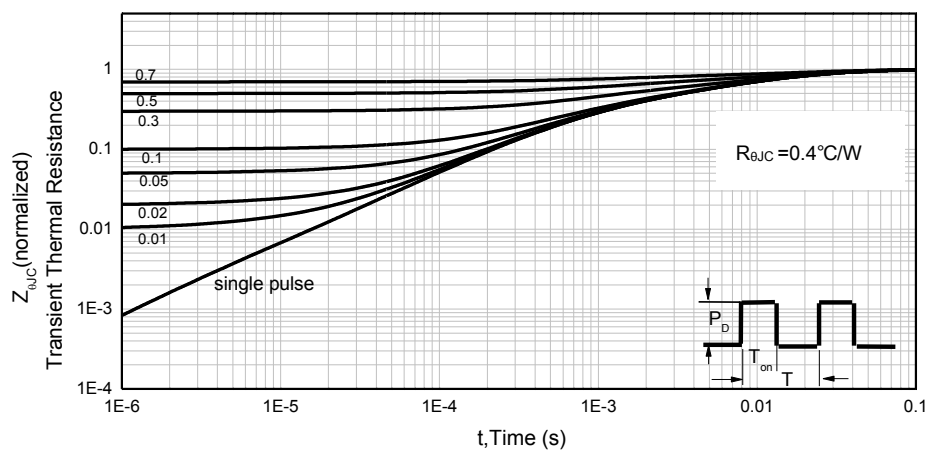
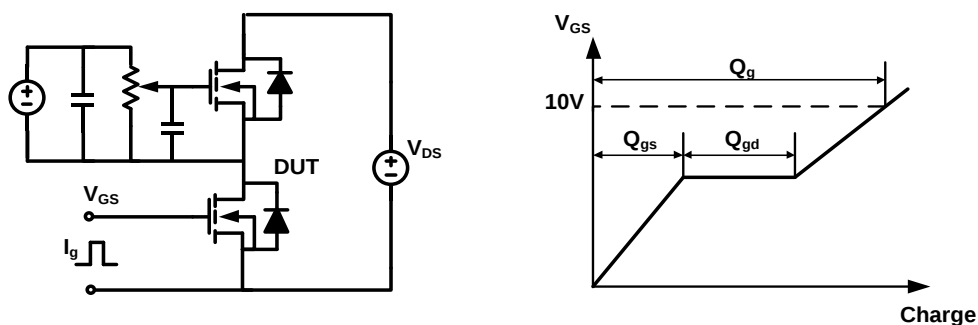


Figure 14. Normalized Maximum Transient Thermal Impedance (R_{thJC})

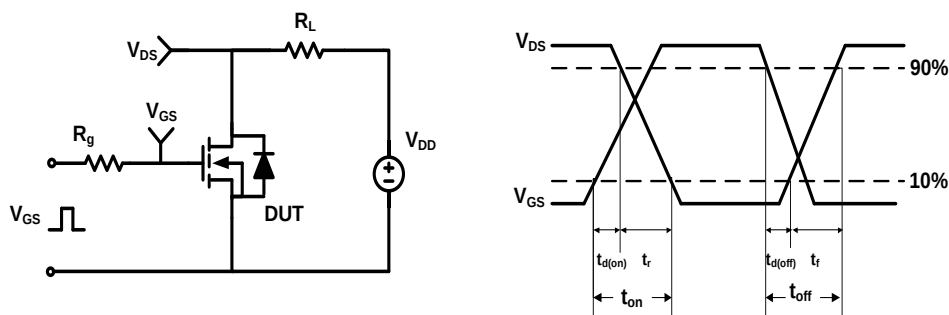


Test Circuit & Waveforms

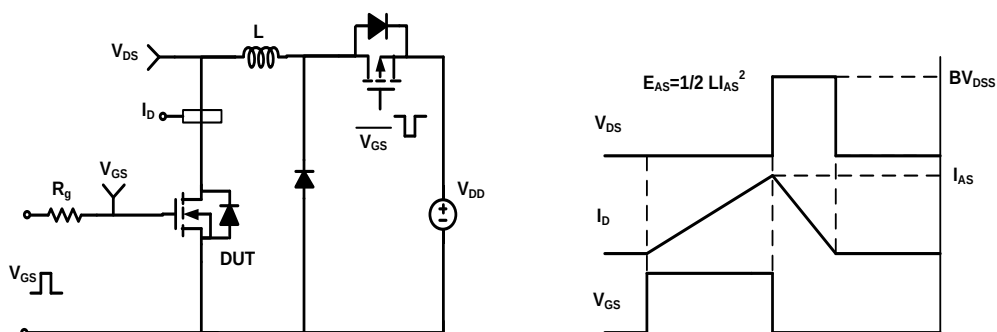
Gate Charge Test Circuit & Waveform



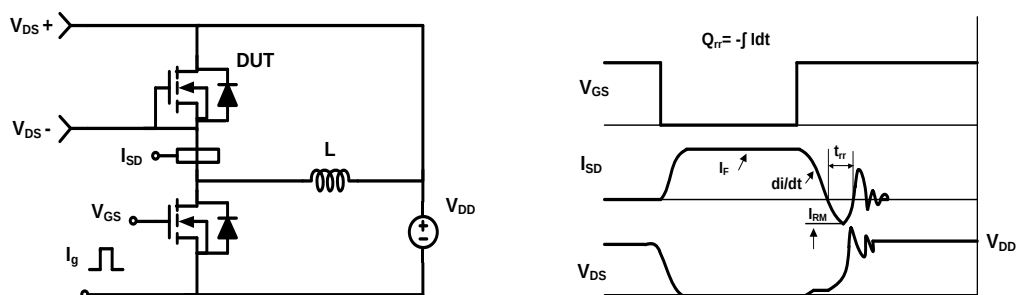
Resistive Switching Test Circuit & Waveform



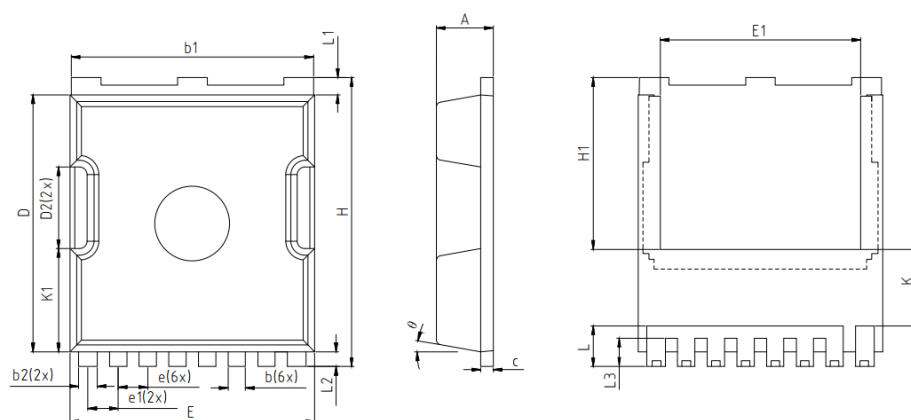
Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Mechanical Dimensions for TOLL



DIMENSIONS IN MILLITMETERS		
SYMBOL	MIN	MAX
A	2.20	2.40
b	0.60	0.80
b1	9.70	9.90
b2	0.65	0.85
c	0.40	0.60
D	10.28	10.58
D2	3.15	3.45
E	9.70	10.10
E1	7.90	8.30
e	1.20 BSC	
e1	1.225 BSC	
H	11.48	11.88
H1	6.95 BSC	
K	3.10 BSC	
K1	4.08	4.28
L	1.40	1.80
L1	0.60	0.80
L2	0.50	0.70
L3	1.00	1.30
θ	10° REF	

Revision History

LSGT085R018

Revision:2022-07-22 ,Rev 1.0

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